

Notice of References Cited	Application/Control No. 10/099,961	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Davienne Monbleau	Art Unit 2828	Page 1 of 1

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	C	US-6198757	03-2001	Broutin et al.	372/32
	D	US-6233263	05-2001	Chang-Hasnain et al.	372/32
	E	US-6289028	09-2001	Munks et al.	372/20
	F	US-5936985	08-1999	Yamamoto et al.	372/38
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NON-PATENT DOCUMENTS

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	V	Yeo et al., "Integration of Waveguide-Type Wavelength Demultiplexing Photodetectors by the Selective Intermixing of an InGaAs-InGaAsP Quantum-Well Structure", IEEE: Journal of Quantum Electronics, Vol. 37, No. 6, June 2001, pages 824-829.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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